

# HAR<sup>®</sup> 3715, HAR 372x, HAR 373x

Robust Dual-Die Programmable  
2D Position Sensor Family  
with Arbitrary Output Function



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## Robust Dual-Die Programmable 2D Position Sensor Family with Arbitrary Output Function

**Release Note: Revision bars indicate significant changes to the previous edition.**

### 1. Introduction

The HAR 37xy is the full redundant (dual-die) version of the well known HAL 37xy family using the TDK-Micronas' proprietary 3D HAL technology. It provides full redundancy due to two independent dies stacked in a single package each bonded on a separate side of the package. The stacked-die architecture ensures that both dies occupy the same magnetic-field position, thus generating synchronous measurement outputs.

This family has several members. HAR 372x provides linear, ratiometric analog output signals with integrated wire-break detection working with pull-up or pull-down resistors. Compared to the HAR 372x the HAR 3715 is splitting the 360° measurement range either into four repetitive 90° (MOD 90°) or three 120° (MOD 120°) segments. HAR 373x features digital output formats like PWM and SENT (according SAE J2716 release 2010). The digital output format is customer programmable. The PWM outputs are configurable with frequencies between 0.2 kHz and 2 kHz with up to 12-bit resolution.

Conventional planar Hall technology is only sensitive to the magnetic field orthogonal to the chip surface. In addition to the orthogonal magnetic field, HAR 37xy is also sensitive to magnetic fields applied in parallel to the chip surface. This is possible by integrating vertical Hall plates into the standard CMOS process.

The sensor cell can measure three magnetic-field components  $B_X$ ,  $B_Y$ , and  $B_Z$ . This enables a new set of applications for position detection, like wide distance, angle or through-shaft angular measurements. The table below describes the different family members.

| Type     | Output Format | Detectable Field Component |
|----------|---------------|----------------------------|
| HAR 3715 | Analog/Modulo | $B_X$ and $B_Y$            |
| HAR 3725 | Analog        | $B_X$ and $B_Y$            |
| HAR 3726 | Analog        | $B_Y$ and $B_Z$            |
| HAR 3727 | Analog        | $B_X$ and $B_Z$            |
| HAR 3735 | PWM & SENT    | $B_X$ and $B_Y$            |
| HAR 3736 | PWM & SENT    | $B_Y$ and $B_Z$            |
| HAR 3737 | PWM & SENT    | $B_X$ and $B_Z$            |

On-chip signal processing calculates the angle out of two of the magnetic-field components and converts this value to an output signal. Due to the measurement method, the sensor exhibits excellent drift performance over the specified temperature range resulting in a new class of accuracy for angular or linear measurements.

Additionally to the built-in signal processing, the sensor features an arbitrary programmable characteristic for linearization of the output signal (with up to 33 setpoints).

Major characteristics like gain and temperature dependent offset of X/Y- and Z-channel, reference position, phase shift between X/Y- and Z-signal, hysteresis, low-pass filter frequency, output slope, and offset and clamping levels can be adjusted to the magnetic circuitry by programming the non-volatile memory.

The sensor contains advanced on-board diagnostic features that enhance fail-safe detection. In addition to standard checks, such as overvoltage and undervoltage detection and wire break, internal blocks such as ROM and signal path are monitored during normal operation. For devices with a selected PWM output, the error modes are indicated by a change of PWM frequency and duty-cycle. For SENT output a dedicated error code will be transmitted.

The devices are designed for automotive and industrial applications and operate with junction temperature from  $-40\text{ °C}$  up to  $170\text{ °C}$ .

The sensors are available in a very small 8-pin SOIC8 package. The package outlines and the X-Y position of the sensitive areas are identical to the single-die version HAL 37xy.

## 1.1. Major Applications

Thanks to its redundancy capability, HAR 37xy can address safety-critical applications according to ISO 26262 rules. Sensor's versatile programming characteristics and its high accuracy, make the HAR 37xy a potential solution for the following applications examples:

- Linear movement measurement,
  - Dual-Clutch transmission
  - Engine stroke sensor
  - Clutch pedal position
  - Cylinder and valve position sensing
- Rotary position measurement, like
  - Gear selector
  - Throttle valve position, etc.
  - Chassis position sensors (ride-height control) with HAR 3715
- Joystick
- Non-contact potentiometer

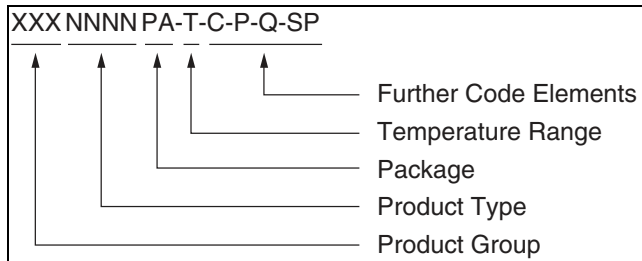
## 1.2. Features

Each die provides

- Angular and position measurement extremely robust against temperature and stress influence
- 12-bit ratiometric linear analog output for HAR 372x
- Modulo 90°/120° for HAR 3715
- 0.2 kHz to 2 kHz PWM (up to 12 bits) or 12-bit SENT output for HAR 373x
- Programmable arbitrary output characteristic with up to 33 setpoints
- 8 kHz sampling frequency
- Operates from 4.5 V up to 5.5 V supply voltage
- Operates from –40 °C up to 170 °C junction temperature
- Programming via the sensor's output pin
- Programmable characteristics in a non-volatile memory (EEPROM) with redundancy and lock function
- Programmable first-order low-pass filter
- Programmable hysteresis on X/Y or Z-channel
- Programmable output gain and offset
- X/Y- and Z-channel gain of signal path programmable
- Second-order temperature dependent offset of signal path programmable for X/Y- or Z-channel
- Phase shift between X/Y- and Z-channel programmable
- Programmable offset before angle calculation block
- Programmable output clamping for error band definition
- Programmable reference position
- Programmable magnetic detection range
- 32-bit identification number for customer
- 32-bit identification number with TDK-Micronas production information (like X,Y position on production wafer)
- On-board diagnostics of different functional blocks of the sensor
- Short-circuit protected push-pull output
- Over- and reverse voltage protection at  $V_{SUP}$
- Under- and overvoltage detection of  $V_{SUP}$
- Wire-break detection with pull-up or pull-down resistor
- EMC and ESD robust design

## 2. Ordering Information

A Micronas device is available in a variety of delivery forms. They are distinguished by a specific ordering code:



**Fig. 2–1:** Ordering Code Principle

For a detailed information, please refer to the brochure: “Sensors and Controllers: Ordering Codes, Packaging, Handling”.

### 2.1. Device-Specific Ordering Code

The HAR 37xy is available in the following package and temperature variant.

**Table 2–1:** Available package

| Package Code (PA) | Package Type |
|-------------------|--------------|
| DJ                | SOIC8-1      |

**Table 2–2:** Available temperature ranges

| Temperature Code (T) | Temperature Range                      |
|----------------------|--|
| A                    | $T_J = -40\text{ °C to }170\text{ °C}$ |

The relationship between ambient temperature ( $T_A$ ) and junction temperature ( $T_J$ ) is explained in Section 5.1. on page 39.

For available variants for Configuration (C), Packaging (P), Quantity (Q), and Special Procedure (SP) please contact TDK-Micronas.

**Table 2–3:** Available ordering codes and corresponding package marking

| Available Ordering Codes | Package Marking |
|--------------------------|-----------------|
| HAR3715DJ-A-[C-P-Q-SP]   | 3715A           |
| HAR3725DJ-A-[C-P-Q-SP]   | 3725A           |
| HAR3726DJ-A-[C-P-Q-SP]   | 3726A           |
| HAR3727DJ-A-[C-P-Q-SP]   | 3727A           |
| HAR3735DJ-A-[C-P-Q-SP]   | 3735A           |
| HAR3736DJ-A-[C-P-Q-SP]   | 3736A           |
| HAR3737DJ-A-[C-P-Q-SP]   | 3737A           |



### 3. Functional Description

#### 3.1. General Function

HAR 3715, HAR 372x and HAR 373x are 2D position sensors based on TDK-Micronas' 3D HAL technology. They are dual-die integrated circuits with full redundant output signals. Each sensor die includes two vertical and one horizontal Hall plate with spinning current offset compensation for the detection of X, Y or Z magnetic-field components, a signal processor for calculation and signal conditioning of two magnetic-field components, protection devices, and a ratiometric linear analog, PWM or SENT output.

The spinning current offset compensation minimizes the errors due to supply voltage and temperature variations as well as external package stress.

The signal path of each die of HAR 37xy consist of two channels (CH1 and CH2). Depending on the product variant two out of the three magnetic-field components are connected to Channel 1 and Channel 2.

The sensors can be used for angle measurements in a range between 0° and 360° (end of shaft and through shaft setup) as well as for robust position detection (linear movement or position). The in-system calibration can be utilized by the system designer to optimize performance for a specific system. The calibration information is stored in an on-chip EEPROM.

The HAR 37xy is programmable by modulation of the output voltage. No additional programming pin is needed.

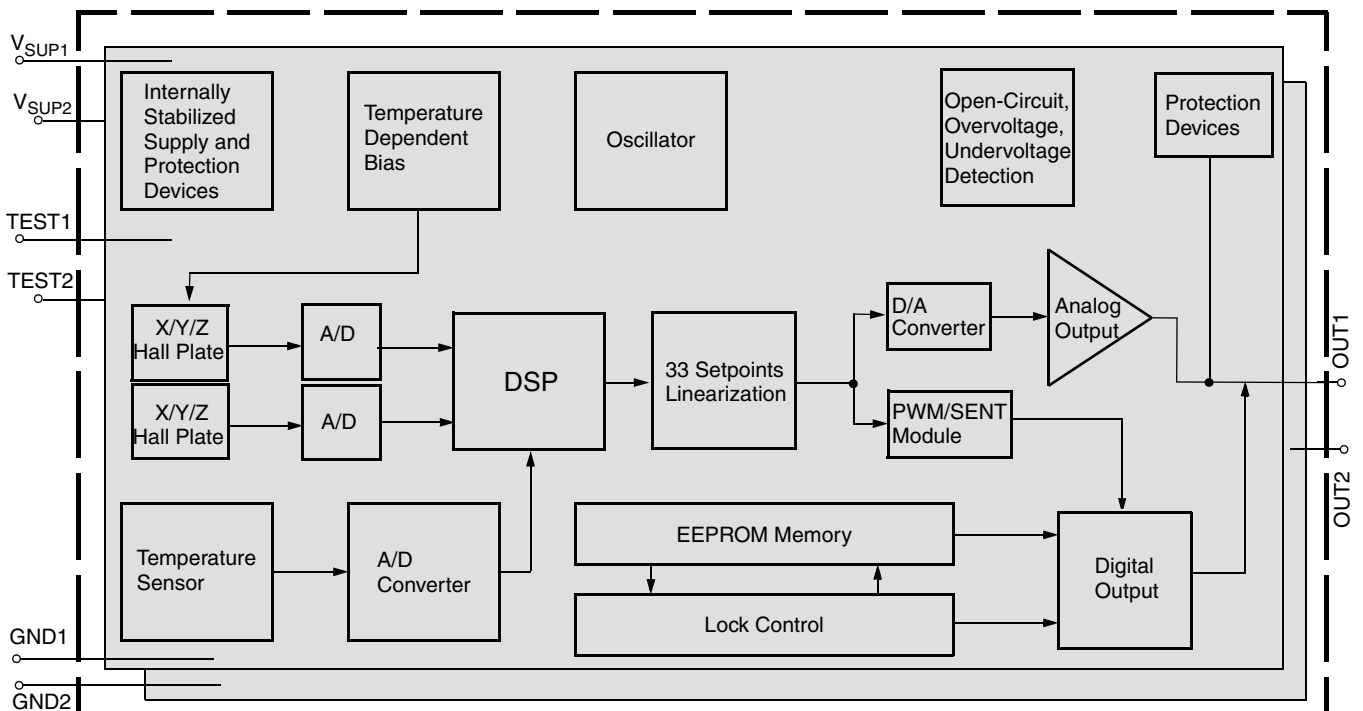


Fig. 3–1: HAR 37xy block diagram

### 3.2. Signal Path and Register Definition

#### 3.2.1. Signal Path

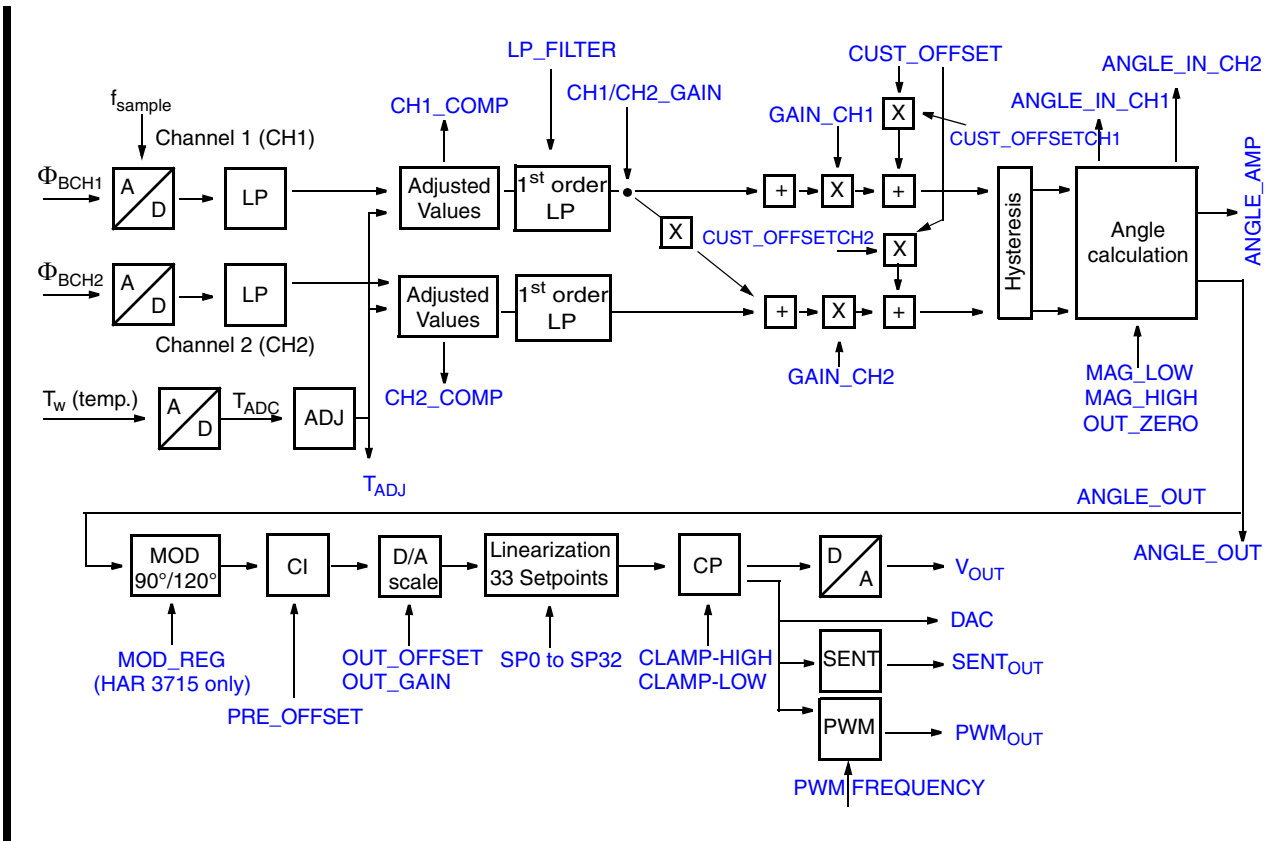


Fig. 3–2: Signal path of HAR 37xy (equal for both dies)

#### 3.2.2. Register Definition

The DSP part of this sensor performs the signal conditioning. The parameters for the DSP are stored in the EEPROM/NVRAM register. Details of the signal path are shown in Fig. 3.2.

#### Terminology:

GAIN: name of the register or register value

Gain: name of the parameter

Blue color: register names

The sensor signal path contains two kinds of registers. Registers that are readout only (RAM) and programmable registers EEPROM/NVRAM. The RAM registers contain measurement data at certain steps of the signal path and the EEPROM/NVRAM registers have influence on the sensors signal processing.

### 3.2.2.1. RAM Registers

#### TADJ

The TADJ register contains the digital value of the sensor junction temperature. It has a length of 16 bits and is binary coded. From the 16 bits only the range between 0 and 32767 is used for the temperature information. Typically the temperature sensor is calibrated in the way that at  $-40^{\circ}\text{C}$  the register value is 100 LSB and at  $160^{\circ}\text{C}$  it is 12000 LSB.

#### CH1\_COMP and CH2\_COMP

CH1\_COMP and CH2\_COMP register contain the temperature compensated magnetic-field information of channel 1 and channel 2. Both registers have a length of 16 bits each and are two's-complement coded. Therefore, the register values can vary between  $-32768$  and  $32767$ .

#### ANGLE\_IN\_CH1 and ANGLE\_IN\_CH2

ANGLE\_IN\_CH1 and ANGLE\_IN\_CH2 register contain the customer compensated magnetic-field information of channel 1 and channel 2 used for the angle calculation. These registers include already customer phase-shift, gain and offset correction as well as an hysteresis. Both registers have a length of 16 bits each and are two's-complement coded. Therefore, the register values can vary between  $-32768$  and  $32767$ .

#### ANGLE\_OUT

The ANGLE\_OUT register contains the digital value of the position calculated by the angle calculation algorithm. It has a length of 16 bits and is binary. From the 16 bits only the range between 0 and 32767 is used for the position information. Position can either be an angular position (angle) or a virtual angle calculated out of two magnetic-field directions in case of linear position measurements.

#### DAC

The DAC register contains the digital equivalent of the output voltage, PWM output duty-cycle or the SENT data. It has a length of 16 bits and is binary. From the 16 bits only the range between 0 and 32767 is used for the position information. Position can either be an angular position (angle) or a virtual angle calculated out of two magnetic-field directions in case of linear position measurements.

## ANGLE\_AMP

The ANGLE\_AMP register contains the digital value of the magnetic-field amplitude calculated by the angle calculation algorithm. From mathematical point of view the amplitude can be calculated out of the signals in channel 1 and channel 2 (X-/Y-/Z-components).

Example:

$$\text{Amplitude} = \sqrt{\text{CH1}^2 + \text{CH2}^2}$$

The angle calculation algorithm adds a factor of roughly 1.6 to the equation for the magnetic amplitude. So the equation for the amplitude is defined as follows:

$$\text{ANGLE\_AMP} \cong 1.6 \times \sqrt{\text{CH1}^2 + \text{CH2}^2}$$

## DIAGNOSIS

The DIAGNOSIS register identifies certain failures detected by the sensor. HAR 37xy performs self-tests during power-up of the sensor and also during normal operation. The result of these self tests is stored in the DIAGNOSIS register. DIAGNOSIS register is a 16-bit register.

| Bit no. | Function                       | Description   |
|---------|--------------------------------|---|
| 15:10   | None                           | Reserved  |
| 9       | DAC Output High Clamping       | This bit is set to 1 in case that the high clamping value of the DAC is reached.  |
| 8       | DAC Output Low Clamping        | This bit is set to 1 in case that the low clamping value of the DAC is reached.   |
| 7       | Channel 1 Clipping             | These bits are set to 1 in case that the A/D converter in channel 1 and/or 2 detects an under- or overflow  |
| 6       | Channel 2 Clipping             |   |
| 5       | DSP Self Test <sup>1)</sup>    | The DSP is doing the internal signal processing like angle calculation, temperature compensation, etc.<br>This bit is set to 1 in case that the DSP self test fails. (Continuously running) |
| 4       | EEPROM Self Test <sup>1)</sup> | This bit is set to 1 in case that the EEPROM self test fails. (Performed during power-up or continuously running)   |
| 3       | ROM Check                      | This bit is set to 1 in case that ROM parity check fails. (Continuously running)  |
| 2       | None                           | Reserved  |
| 1       | MAGHI                          | This bit is set to 1 in case that the magnetic field is exceeding the MAG-HI register value (magnetic field too high)   |
| 0       | MAGLO                          | This bit is set to 1 in case that the magnetic field is below the MAG-LOW register value (magnetic field too low)   |

1) Details on the sensor self tests can be found in Section 3.5. on page 21.

## PROG\_DIAGNOSIS

The PROG\_DIAGNOSIS register allows the customer to identify errors occurring during programming and writing of the EEPROM or NVRAM memory. The customer must check the first and second acknowledge. To enable debugging of the production line it is recommended to read back the PROG\_DIAGNOSIS register in case of a missing second acknowledge. Please check the Programming Guide for HAR 37xy for further details.

The PROG\_DIAGNOSIS register is a 16-bit register. The following table shows the different bits indicating certain error possibilities.

| Bit no. | Function                           | Description   |
|---------|------------------------------------|---|
| 15:11   | None                               | Reserved  |
| 10      | Charge Pump Error                  | This bit is set to 1 in case that the internal programming voltage was too low                    |
| 9       | Voltage Error during Program/Erase | This bit is set to 1 in case that the internal supply voltage was too low during program or erase |
| 8       | NVRAM Error                        | This bit is set to 1 in case that the programming of the NVRAM failed                             |
| 5:0     | Programming                        | These bits are used for programming the memory  |

### 3.2.2.2. EEPROM Registers

**Note** For production and qualification tests it is mandatory to set the LOCK bit after final adjustment and programming.

**Note** Please refer to the “HAL 37xy, HAR 372x, HAR 373x User Manual” for further details on register settings/calculation and programming of the device.

#### TDK-Micronas ID's

The MIC\_ID1 and MIC\_ID2 registers are both 16-bit organized. They are read only and contain TDK-Micronas production information, like X/Y position on the wafer, wafer number, etc.

#### Customer ID's

The CUST\_ID1 and CUST\_ID2 registers are both 16-bit organized. These two registers can be used to store customer production information, like serial number, project information, etc.

## CH1/CH2\_GAIN

CH1/CH2\_GAIN can be used to compensate a phase shift between channel 1 and channel 2. The register has a length of 16 bits. It is possible to make a phase-shift correction of  $\pm 75^\circ$ . The step size and therefore the smallest possible correction is  $0.002^\circ$ . The register is two's-complement coded and ranges from  $-32768$  to  $32767$ . The register value is sin function based.

Neutral value for this register is zero (no phase-shift correction).

---

**Note** In case the phase-shift correction is used, then it is necessary to adapt the settings of GAIN\_CH2 too. For details see definition of GAIN\_CH2.

---

## GAIN\_CH1 and GAIN\_CH2

GAIN\_CH1 and GAIN\_CH2 can be used to compensate amplitude mismatches between channel 1 and channel 2. TDK-Micronas delivers pre calibrated sensors with compensated gain mismatch between channel 1 and channel 2. Nevertheless it is possible that due to the magnetic circuit a mismatch between channel 1 and channel 2 gain occurs. This can be compensated with GAIN\_CH1 and GAIN\_CH2.

Both registers have a length of 16 bits and are two's-complement coded. Therefore, they can have values between  $-32768$  and  $32767$  ( $-2$  to  $2$ ). For neutral settings both register values have to be set to 1 (register value 16384).

In case that the phase-shift correction is used it is necessary to change also the gain of channel 2 (see also CH1/CH2\_GAIN). If phase-shift correction is used the corresponding register has to be set to

$$\text{GAIN\_CH2} = \frac{16384}{\cos(\text{phase shift})}$$

---

**Note** In case GAIN\_CH1 or GAIN\_CH2 exceed the range of  $-2$  to  $2$  ( $-32768$  to  $32767$ ), then it is possible to reduce the gain of the opposite channel for compensation.

---

## CUST\_OFFSET

CUST\_OFFSET can be used to compensate an offset in channel 1 and channel 2. TDK-Micronas delivers pre calibrated sensors. Nevertheless it is possible that due to the magnetic circuit an offset in channel 1 and channel 2 occurs. This can be compensated with CUST\_OFFSET.

The customer offset can also have a temperature coefficient to follow the temperature coefficient of a magnet. The customer offset consists of a polynomial of second-order represented by the three registers CUST\_OFFSET1...3.

The customer offset can be added to channel 1 and/or channel 2 by the selection coefficients CUST\_OFFSETCH1 and CUST\_OFFSETCH2. Additionally these two registers can be used to scale the temperature dependent offset between 0% and 100%

All five registers have a length of 16 bits and are two's-complement coded. Therefore, they can have values between -32768 and 32767.

## HYSTERESIS

HYSTERESIS defines the number of digital codes used as an hysteresis on channel 1 and channel 2 before the angle calculation. The purpose of this register is to avoid angle variation on the ANGLE\_OUT register and finally on the output signal due to the noise on the ANGLE\_IN\_CH1 and ANGLE\_IN\_CH2 signals.

The register has a length of 16 bits and is two's complement number.

It is possible to program a hysteresis between 1 LSB and 16383 LSB. The register value itself must be stored as a negative value.

The hysteresis function is deactivated by setting the register value to zero.

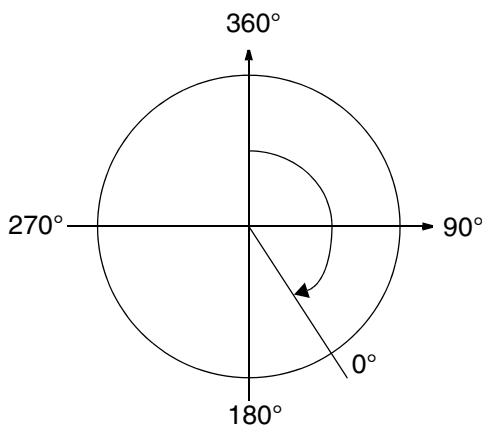
## OUT\_ZERO

OUT\_Zero defines the reference position for the angle output. It can be set to any value of the output range. It is the starting point/reference for the 33 setpoints. OUT\_ZERO has a register length of 16 bits and it is two's-complement coded.

---

**Note** Before reading ANGLE\_OUT it is necessary to set OUT\_ZERO to 0.

---



**Fig. 3–3:** Example definition of zero degree point

Secondly this angle can be used to shift the PI discontinuity point of the angle calculation to the maximum distance from the required angular range in order to avoid the 360°-wrapping of the output due to noise.

## PRE\_OFFSET

The PRE\_OFFSET register allows to shift the angular range to avoid an overflow of the internal 16-bit calculation/signal path.

The PRE\_OFFSET register has a length of 16 bits and is two's-complement coded.

## OUT\_GAIN

OUT\_GAIN defines the gain of the output signal. The register has a length of 16 bits and is two's-complement coded. OUT\_GAIN = 1 is neutral setting and leads to a change of the output signal from 0% to 100% for an angle change from 0° to 360° (if OUT\_OFFSET is set to 0).

OUT\_GAIN can be changed between -64 and 64.



## OUT\_OFFSET

OUT\_OFFSET defines the offset of the output signal. The register has a length of 16 bits and is two's complement coded. OUT\_OFFSET = 0 is neutral setting and leads to a change of the output signal from 0% to 200% of full scale for an angle change from 0° to 360° (If OUT\_GAIN is set to 1).

OUT\_Offset can be changed between -200% and 200% of full scale. OUT\_OFFSET = 0 leads to a voltage offset of 0% of full scale and OUT\_OFFSET = 32768 leads to a offset of -200% of  $V_{SUP}$ .

## Clamping Levels (CLAMP-LOW & CLAMP-HIGH)

The clamping levels CLAMP\_LOW and CLAMP\_HIGH define the maximum and minimum output voltage of the analog output. The clamping levels can be used to define the diagnosis band for the sensor output. Both registers have a length of 16 bits and are two's-complemented coded. Both clamping levels can have values between 0% and 100% of full scale.

## Magnetic Range Check

The magnetic range check uses the magnitude output and compares it with an upper and lower limit threshold defined by the registers MAG-LOW and MAG-HIGH. If either low or high limit is exceeded then the sensor will indicate it with an overflow on the sensors output (output high clamping).

## MAG-LOW

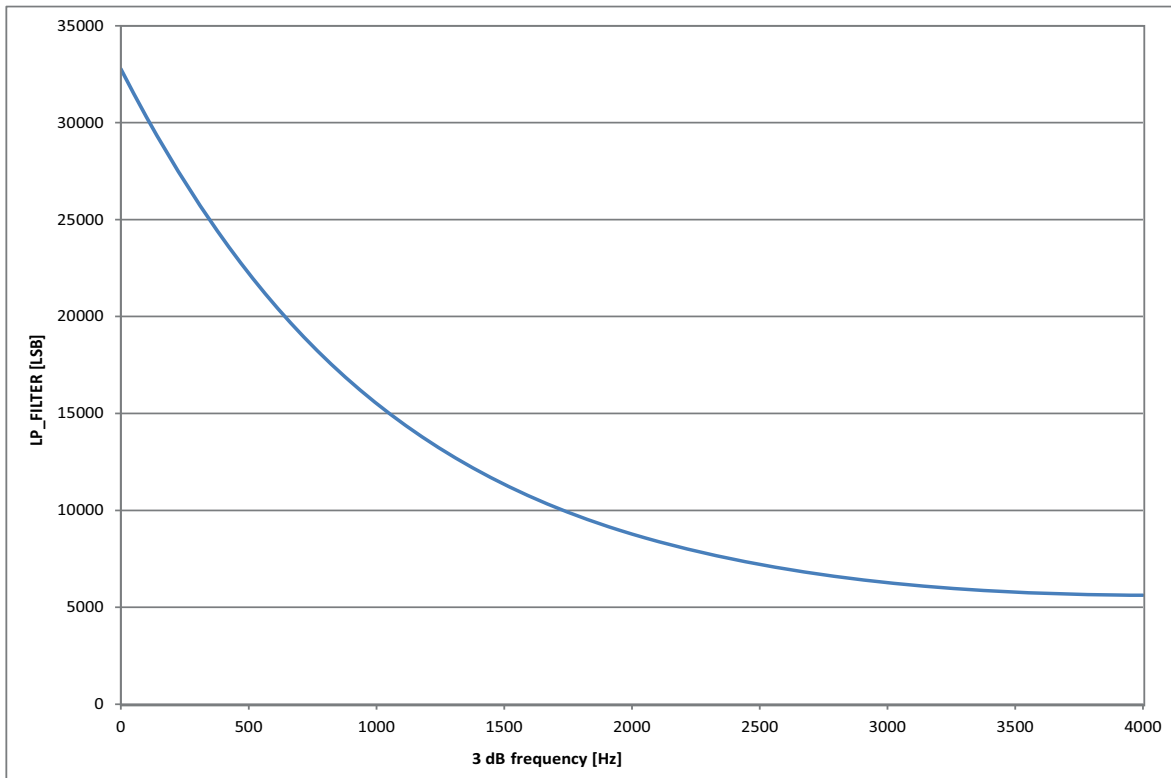
MAG-LOW defines the low level for the magnetic-field range check function. This register has a length of 16 bits and is two's complement number.

## MAG-HIGH

MAG-HIGH defines the high level for the magnetic-field range check function. This register has a length of 16 bits and is two's complement number.

## Low-Pass Filter

With the LP\_Filter register it is possible to select different  $-3\text{dB}$  frequencies for HAR 37xy. The low-pass filter is a first-order digital filter and the register is 16-bit organized. Various typical filter frequencies between 4 kHz (no filter) and 10 Hz are available.



**Fig. 3–4:** 3dB filter frequency vs. LP\_FILTER codes

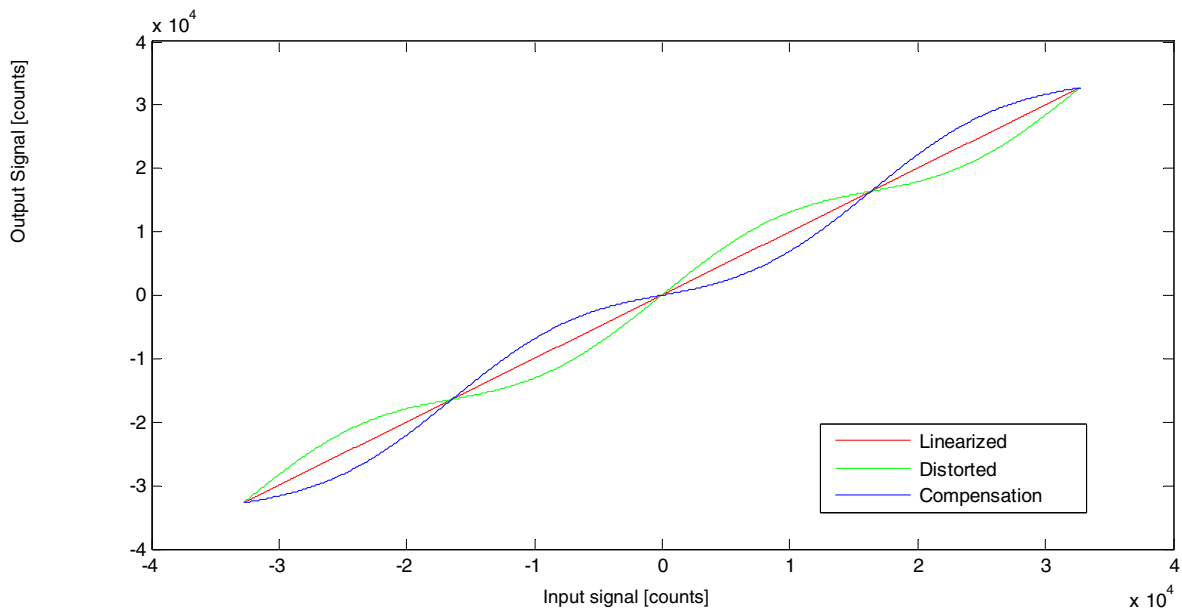
## Modulo Select

The MODULO\_Select register is only available in HAR 3715. With this register, the customer can switch between Modulo  $90^\circ$  and  $120^\circ$  output.

HAR 3715 is splitting the  $360^\circ$  measurement range either into four repetitive  $90^\circ$  (MOD  $90^\circ$ ) or three  $120^\circ$  (MOD  $120^\circ$ ) segments.

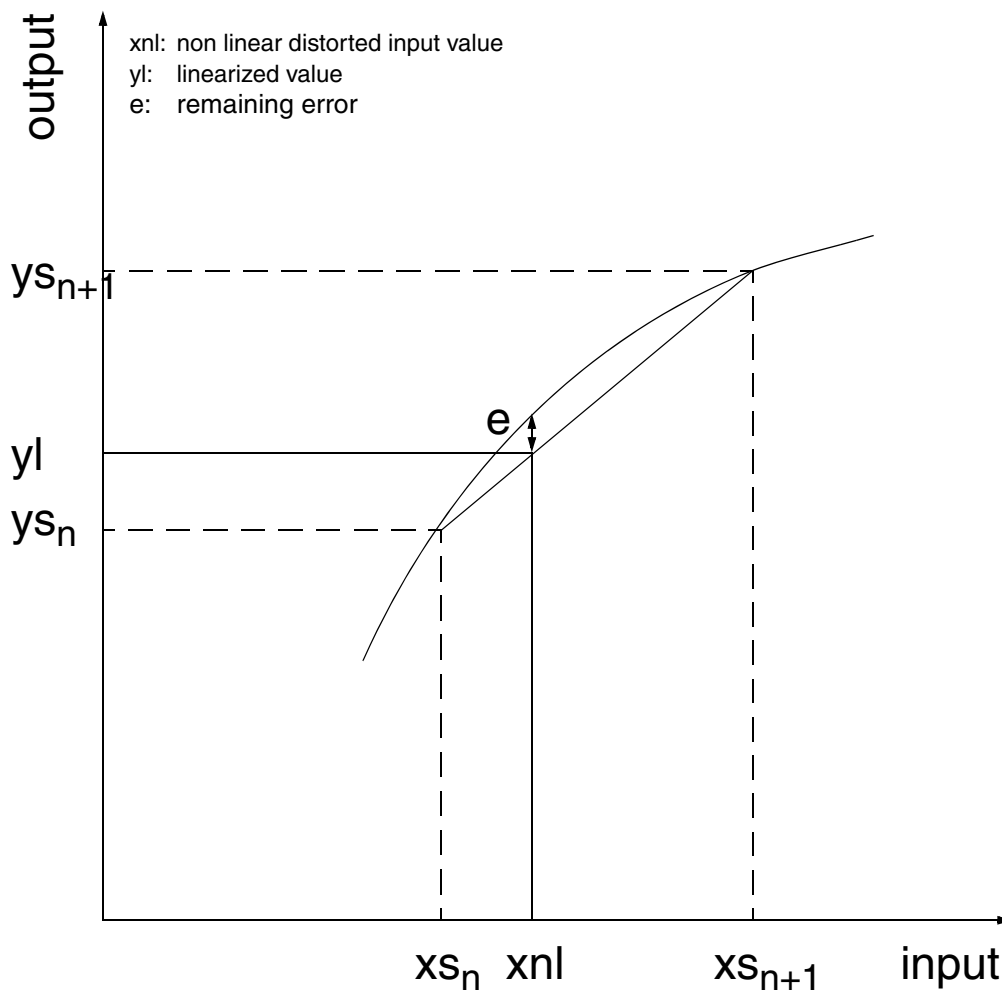
### 3.3. Output Linearization

In certain applications (e.g. through shaft applications or position measurements) it is required to linearize the output characteristic. The resulting output characteristic “value vs. angle/position” is not a linear curve as in the ideal case. But it can be linearized by applying an inverse nonlinear compensation curve.



**Fig. 3–5:** Example for output linearization

For this purpose the compensation curve will be divided into 33 segments with equal distance. Each segment is defined by two setpoints, which are stored in EEPROM. Within the interval, the output is calculated by linear interpolation according to the position within the interval.



**Fig. 3–6: Linearization - detail**

The constraint of the linearization is that the input characteristic has to be a monotonic function. In addition, it is recommended that the input does not have a saddle point or inflection point, i.e. regions where the input is nearly constant. This would require a high density of set points.

To do a linearization the following steps are necessary:

- Measure output characteristics over full range
- Find the inverse (point-wise mirroring the graph on the bisectrix)
- Do a spline fit on the inverse
- Insert digital value of set point position into spline fit function for each set point (0, 1024, 2048 ... 32768)
- Resulting values can be directly entered into the EEPROM

### 3.4. NVRAM Register

#### Customer Setup

The CUST\_SETUP register is a 16-bit register that enables the customer to activate various functions of the sensor like diagnosis modes, functionality mode, customer lock, communication protocol speed, etc.

**Table 3–1:** Customer Setup Register

| Bit no. | Function                  | Description   |
|---------|---------------------------|---|
| 15      | None                      | Reserved  |
| 14      | EEPROM Self-Test          | EEPROM Self-Test Mode (latched)<br>0: Running during Power-Up<br>1: Continuously  |
| 13      | Communication speed       | BiPhase-M protocol speed<br>0: typ. 1 ms<br>1: typ. 0.25 ms   |
| 12      | DIGMOD                    | Output format for HAR 373x devices<br>0: PWM output<br>1: SENT output   |
| 11:10   | PWMFREQ                   | Defines the frequency of the PWM output for HAR 373x devices only<br>0: 1 kHz<br>1: 500 Hz<br>2: 200 Hz<br>3: 2 kHz (11 bits)   |
| 9:8     | Output Short Detection    | 0: Disabled<br>1: High & low side over current detect. Error Band = High: OUT = V <sub>SUP</sub><br>Error Band = Low: OUT = GND<br>2: High & low side over current detect. Error Band = High: OUT = GND<br>Error Band = Low: OUT = V <sub>SUP</sub><br>3: Low side over current detection<br>OUT = Tristate in error case |
| 7       | Error Band                | Error band selection for locked devices (Customer Lock bit set).<br>0: High error band (V <sub>SUP</sub> )<br>1: Low error band (GND)<br>The sensor will always go to high error band as long as it is not locked (Customer Lock bit not set).  |
| 6       | Burn-In Mode              | 0: Disabled<br>1: Enabled   |
| 5       | Functionality Mode        | 0: Extended<br>1: Normal<br>(see Section 4.9. on page 31)   |
| 4       | Communication Mode (POUT) | Communication via output pin<br>0: Disabled<br>1: Enabled   |
| 3       | Overvoltage Detection     | 0: Overvoltage detection active<br>1: Overvoltage detection disabled  |

**Table 3–1:** Customer Setup Register, continued

| Bit no. | Function        | Description   |
|---------|-----------------|---|
| 2       | Diagnosis Latch | Latching of diagnosis bits<br>0: No latching<br>1: Latched till next POR (Power-On Reset)               |
| 1       | Diagnosis       | 0: Diagnosis errors force output to error band<br>1: Diagnosis errors do not force output to error band |
| 0       | Customer Lock   | Bit must be set to 1 to lock the sensor memory  |

The Output Short Detection feature is implemented to detect a short circuit between two sensor outputs. The customer can define how the sensor should signalize a detected short circuit (see table above). The time interval in which the sensor is checking for an output short and the detectable short circuit current are defined in Section 4.9. on page 31.

This feature should only be used in case that two sensors are used in one module to detect a short between their outputs. In case that the Output Short Detection is not active both sensors will try to drive their output voltage and the resulting voltage will be within the valid signal band.

---

**Note** The Output Short Detection feature is only active after setting the Customer Lock bit and a power-on reset.

---

### 3.5. On-board Diagnostic Features

The HAR 37xy features two groups of diagnostic functions. The first group contains basic functions that are always active. The second group can be activated by the customer and contains supervision and self-tests related to the signal path and sensor memory.

#### Diagnostic features that are always active:

- Wire break detection for supply and ground line
- Undervoltage detection
- Thermal supervision of output stage (overcurrent, short circuit, etc.)
- EEPROM self-test at power-on

#### Diagnostic features that can be activated by customer:

- continuous EEPROM self-test
- ROM parity check
- Output signal clamping
- A/D converter clipping
- Continuous DSP self-test
- Magnetic range detection
- Overvoltage detection

In case of HAR 3715 and HAR 372x, the sensor indicates a fault immediately by switching the output signal to the selected error band in case that the diagnostic mode is activated by the customer. The customer can select if the output goes to the upper or lower error band by setting bit number 7 in the CUST\_SETUP register (Table on page 21). An output short drives the output to VSUP, GND or tristate depending of the customer settings as described in Table 3–1 on page 21. Further details can be found in Section 4.9. on page 31.

The sensor switches the output to tristate if an over temperature is detected by the thermal supervision. The sensor switches the output to ground in case of a VSUP wire break and to VSUP in case of a GND wire break.

HAR 373x indicates a failure by changing the PWM frequency. The different errors are then coded in different duty-cycles.

**Table 3–2:** Failure indication for HAR 373x

| Failure Mode                  | Frequency | Duty-Cycle |
|-------------------------------|-----------|------------|
| EEPROM, ROM and DSP self-test | 50%       | 95%        |
| Magnetic field too low        | 50%       | 62.5%      |
| Magnetic field too high       | 50%       | 55%        |
| Overvoltage                   | 50%       | 75%        |
| Undervoltage                  | No PWM    | n.a.       |
| A/D converter clipping        | 50%       | 70%        |

In case of undervoltage, the PWM signal will be constantly 'high' or 'low' depending on the setting of bit number 7 in the CUST\_SETUP register. Default setting is 'high' level.

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**Note** In case of an error the sensor changes the selected PWM frequency.  
Example: During normal operation the PWM frequency is 1 kHz, in case of an error 500 Hz.

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### 3.6. SENT Output

The implementation of the SENT (Single Edge Nibble Transmission) interface of HAR 373x is according SAE J2716 release 2010-01.

Fig. 3–7 shows the general SENT protocol format. Every transmission starts with a low pulse. The signal is transmitted by the sensor as a series of pulses and data measured as falling to falling edge times.

The SENT telegram consists of a synchronization / calibration period, a status & communication nibble, three data nibbles, and a CRC nibble and a pause period. See Section 4.9. on page 31 for the timing parameters of a telegram.

All timing values in a SENT protocol are referenced to the clock tick time  $t_{\text{tick}}$ .

After reset the output is recessive high. The transmission starts with a low pulse of the synchronization phase (Fig. 3–7). Every low pulse has the same length specified by the parameter  $t_{\text{nlow}}$ . The synchronization period has always the same length of clock cycles. The clock variation is included in the parameter  $t_{\text{sync}}$ . The following status and data nibbles always start with a low pulse with  $t_{\text{nlow}}$ . The nibble high time of the status  $t_{\text{stat}}$ , the data  $t_{\text{d3,2,1}}$  and the CRC  $t_{\text{crc}}$  depends on the transmitted value. Therefore, the message time of a SENT message depends on the tick time and the value which is transmitted by the message.

In order to synchronize the SENT messages to the measurement sampling rate an additional pause period is added, which is transmitted after the checksum nibble.

The time to transmit one message is calculated by:

$$t_{\text{message}} = t_{\text{sync}} + t_{\text{stat}} + t_{\text{d3}} + t_{\text{d2}} + t_{\text{d1}} + t_{\text{crc}}$$

The checksum nibble is a 4-bit CRC of the data nibbles only. The status & communication nibble is not included in the CRC calculation. The CRC is calculated using polynomial  $x^4 + x^3 + x^2 + 1$  with seed value of 5. See SAE J2716 for further CRC implementation details.

As recommended by the SAE J2716 an additional zero nibble in addition to the 3 data nibbles for the CRC calculation has been implemented. This is a safety measure against common errors in the last data nibble and the checksum.

In HAR 373x the transmitted data nibbles are generated based on the DAC register value. Special data codes have been implemented for error indication via the SENT interface. The angular or linear position information is coded in the signal range from 2 to 4087 LSB in the 12-bit range. Table 3–3 gives an overview on the data nibble content.

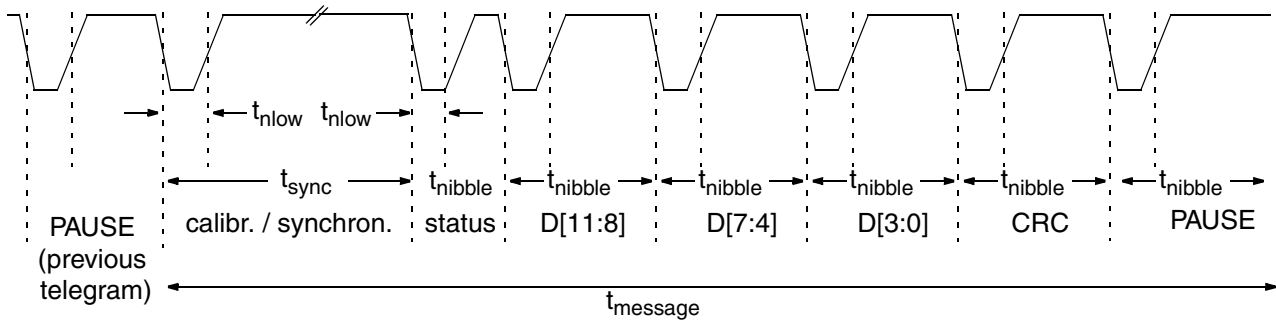
HAR 373x is not using the status nibble for additional information transmission.



**Table 3–3:** Data Nibble Content SENT

| 12-bit value | Definition   |
|--------------|--|
| 4092 to 4095 | Reserved   |
| 4091         | Device Error: Device is failing in one of the self tests (EEPROM, ROM, DSP, Overvoltage)       |
| 4090         | Signal Path Error: MAG-HIGH or -LOW are exceeded, adder overflow or clipping of channel 1 or 2 |
| 4089         | Reserved   |
| 4088         | Clamp-High: Upper signal range violation   |
| 2 to 4087    | Angular or Position information  |
| 1            | Clamp-Low: Lower signal range violation  |
| 0            | During Initialization - Power Up   |

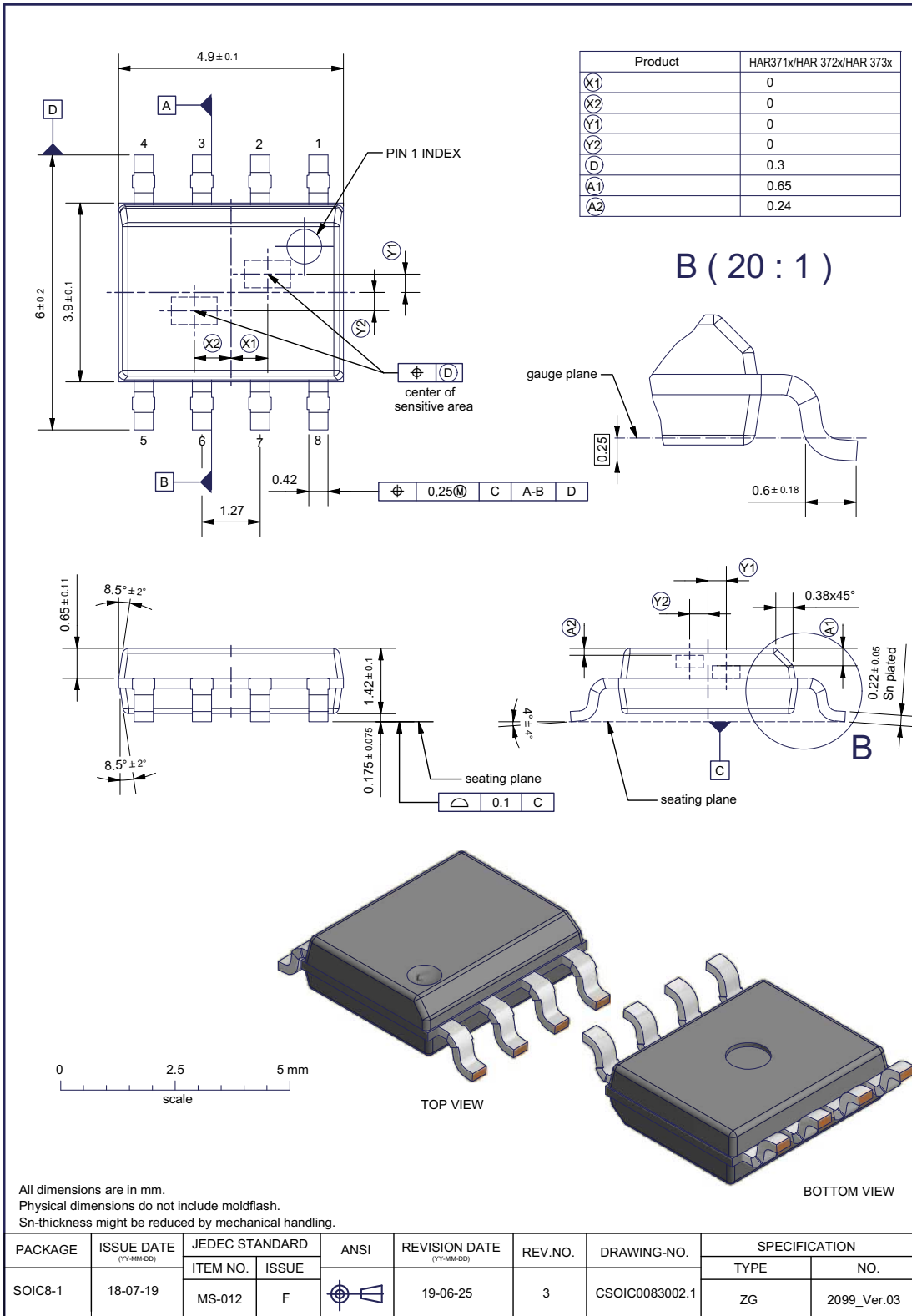
The SENT protocol starts after the initialization time of the sensor to ensure valid data after power-up.



**Fig. 3–7:** SENT protocol format with 3 data nibbles and pause period

# 4. Specifications

## 4.1. Outline Dimensions



All dimensions are in mm.  
Physical dimensions do not include moldflash.  
Sn-thickness might be reduced by mechanical handling.

| PACKAGE | ISSUE DATE<br>(YY-MM-DD) | JEDEC STANDARD |       | ANSI | REVISION DATE<br>(YY-MM-DD) | REV.NO. | DRAWING-NO.    | SPECIFICATION |             |
|---------|--------------------------|----------------|-------|------|-----------------------------|---------|----------------|---------------|-------------|
|         |                          | ITEM NO.       | ISSUE |      |                             |         |                | TYPE          | NO.         |
| SOIC8-1 | 18-07-19                 | MS-012         | F     |      | 19-06-25                    | 3       | CSOIC0083002.1 | ZG            | 2099_Ver.03 |

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**Fig. 4-1:**  
**SOIC8-1:** Plastic small outline IC package, 8 leads, gullwing bent, 150 mil  
 Ordering code: DJ  
 Weight approximately 0.076 g

## 4.2. Soldering, Welding, Assembly

Information related to solderability, welding, assembly, and second-level packaging is included in the document “Guidelines for the Assembly of Micronas Packages”.

It is available on the TDK-Micronas website (<http://www.micronas.com/en/service-center/downloads>) or on the service portal (<http://service.micronas.com>).

## 4.3. Storage and Shelf Life

Information related to storage conditions of Micronas sensors is included in the document “Guidelines for the Assembly of Micronas Packages”. It gives recommendations linked to moisture sensitivity level and long-term storage.

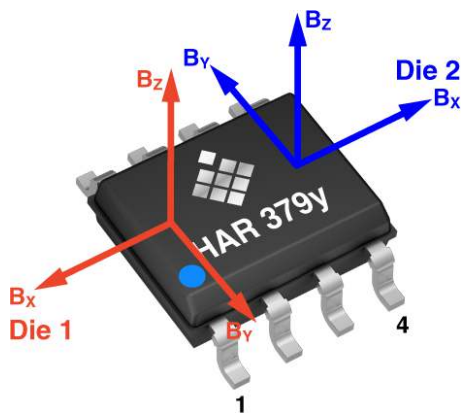
It is available on the TDK-Micronas website (<http://www.micronas.com/en/service-center/downloads>) or on the service portal (<http://service.micronas.com>).

## 4.4. Size of Sensitive Area

Hall plate are =  $275\ \mu\text{m} \times 275\ \mu\text{m}$

See Fig. 4-1 on page xy for more information on the Hall plate position.

## 4.5. Definition of Magnetic-Field Vectors

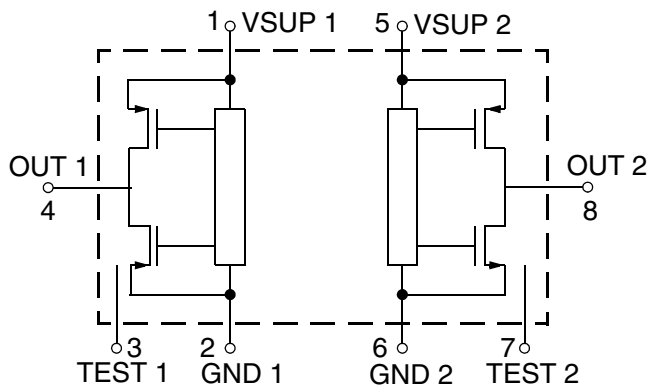


### Note

Die 2 is  $180^\circ$  rotated in relation to die 1. Therefore the measurement values of X and Y components have opposite signs compared to die 1.

## 4.6. Pin Connections and Short Description

| Pin No. | Pin Name | Type   | Short Description                      |
|---------|----------|--------|--|
| Die 1   |          |        |  |
| 1       | VSUP1    | SUPPLY | Supply Voltage Pin1                    |
| 2       | GND1     | GND    | Ground 1                               |
| 3       | TEST1    | I/O    | Test 1                                 |
| 4       | OUT1     | I/O    | Push-Pull Output and Programming Pin 1 |
| Die 2   |          |        |  |
| 5       | VSUP2    | SUPPLY | Supply Voltage Pin 2                   |
| 6       | GND2     | GND    | Ground 2                               |
| 7       | TEST2    | I/O    | Test 2                                 |
| 8       | OUT2     | I/O    | Push-Pull Output and Programming Pin 2 |



**Fig. 4–2:** Pin configuration

**Note** It is recommended to connect the TEST1 pin to GND1 and to connect the TEST2 pin to GND2

## 4.7. Absolute Maximum Ratings

Stresses beyond those listed in the “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only. Functional operation of the device at these conditions is not implied. Exposure to absolute maximum rating conditions for extended periods will affect device reliability.

This device contains circuitry to protect the inputs and outputs against damage due to high static voltages or electric fields; however, it is advised that normal precautions be taken to avoid application of any voltage higher than absolute maximum-rated voltages to this high-impedance circuit.

All voltages listed are referenced to ground (GND).

| Symbol  | Parameter                                     | Pin                      | Min.      | Max.      | Unit | Condition  |
|---|---|--------------------------|-----------|-----------|------|--|
| $V_{SUP}$   | Supply Voltage                                | VSUPx                    | -18       | 18        | V    | $t < 1 \text{ h}^{3)}$                                 |
| $V_{OUT}$   | Output Voltage                                | OUTx                     | -6        | 18        | V    | $t < 1 \text{ h}^{3)}$                                 |
| $V_{OUT} - V_{SUP}$   | Excess of Output Voltage over Supply Voltage  | VSUPx, OUTx              | -         | 2         | V    |  |
| $I_{OUT}$   | Continuous Output Current                     | OUTx                     | -10       | 10        | mA   |  |
| $T_J$   | Junction Temperature under Bias               | -                        | -50       | 190       | °C   | 1)   |
| $T_{storage}$   | Transportation/Short Term Storage Temperature | -                        | -50       | 150       | °C   | Device only without packing material                   |
| $B_{max}$   | Magnetic Field                                | -                        | unlimited | unlimited | T    |  |
| $V_{ESD}$   | ESD Protection                                | VSUPx, OUTx, GNDx, TESTx | -2        | 2         | kV   | 2) For all pin combinations (including die 1 to die 2) |
|   |   | VSUP1, OUT1, GND1, TEST1 | -4        | 4         | kV   | 2) For all pin combinations (die 1 only)               |
|   |   | VSUP2, OUT2, GND2, TEST2 | -4        | 4         | kV   | 2) For all pin combinations (die 2 only)               |
| 1) For 96 h - Please contact TDK-Micronas for other temperature requirements<br>2) AEC-Q100-002 (100 pF and 1.5 kΩ)<br>3) No cumulated stress |   |                          |           |           |      |  |

## 4.8. Recommended Operating Conditions

Functional operation of the device beyond those indicated in the “Recommended Operating Conditions/Characteristics” is not implied and may result in unpredictable behavior, reduce reliability and lifetime of the device.

All voltages listed are referenced to ground (GNDx).

| Symbol           | Parameter   | Pin   | Min. | Typ. | Max. | Unit   | Condition   |
|------------------|---|-------|------|------|------|--------|---|
| V <sub>SUP</sub> | Supply Voltage of one die                         | VSUPx | 4.5  | 5.0  | 5.5  | V      | Normal Operation<br>During Programming                      |
|                  |   |       | 5.7  | 6.0  | 6.5  | V      |   |
| I <sub>OUT</sub> | Continuous Output Current                         | OUTx  | −1.2 | –    | 1.2  | mA     | HAR 3715 and<br>HAR 372x<br>HAR 373x                        |
|                  |   |       |      | –    | 5.5  | mA     |   |
| R <sub>L</sub>   | Load Resistor                                     | OUTx  | 5    | 10   | –    | kΩ     | HAR 3715 and<br>HAR 372x<br>pull-up & pull-down<br>resistor |
|                  |   |       | 1    | –    | –    | kΩ     |   |
| C <sub>L</sub>   | Load Capacitance                                  | OUTx  | 0.33 | 47   | 330  | nF     | HAR 3715 and<br>HAR 372x<br>HAR 373x                        |
|                  |   |       | –    | –    | 1    | nF     |   |
| N <sub>PRG</sub> | Number of Memory Programming Cycles <sup>1)</sup> | –     | –    | –    | 100  | cycles | 0 °C < T <sub>amb</sub> < 55 °C                             |
| B <sub>AMP</sub> | Recommended Magnetic-Field Amplitude              | –     | ±20  | –    | ±100 | mT     |   |
| T <sub>J</sub>   | Junction Temperature <sup>2)</sup>                | –     | −40  | –    | 170  | °C     | for 1000 h  |

<sup>1)</sup> The EEPROM is organized in three banks. Each bank contains up to 32 addresses. It is not allowed to program only one single address within one of the three banks. In case of programming one single address the complete bank has to be programmed.

<sup>2)</sup> Depends on the temperature profile of the application. Please contact TDK-Micronas for life time calculations.

### Note

It is also possible to operate the sensor with magnetic fields down to ±5 mT. For magnetic fields below ±20 mT the sensor performance will be reduced.

## 4.9. Characteristics

at  $T_J = -40\text{ °C}$  to  $170\text{ °C}$ ,  $V_{SUPx} = 4.5\text{ V}$  to  $5.5\text{ V}$ ,  $GNDx = 0\text{ V}$ , after programming and locking of the sensor, at Recommended Operation Conditions if not otherwise specified in the column “Conditions”.

Typical Characteristics for  $T_J = 25\text{ °C}$  and  $V_{SUPx} = 5\text{ V}$ .

| Symbol  | Parameter   | Pin   | Limit Values |            |             | Unit        | Test Conditions  |
|---|---|-------|--------------|------------|-------------|-------------|--|
|   |   |       | Min.         | Typ.       | Max.        |             |  |
| $I_{SUP}$   | Supply Current over Temperature Range                                     | VSUPx | –            | 8          | 13          | mA          | Current consumption of each die  |
|   | Resolution <sup>1)</sup>  | OUTx  | –            | 12         | –           | bit         | For HAR 3715/HAR 372x ratio-metric to VSUPx<br>For HAR 373x (depends on PWM Period)              |
|   |   |       | –            | 12         | –           | bit         |  |
| $t_{Startup}$   | Start-up Time <sup>2)</sup>   | OUTx  | –            | –          | 1.7         | ms          | $C_L = 10\text{ nF}$ (see Fig. 4–3 on page 35)   |
| <b>Overvoltage and Undervoltage Detection</b>   |   |       |              |            |             |             |  |
| $V_{SUP,UV}$  | Undervoltage Detection Level  | VSUPx | 3.3<br>3.1   | 3.9<br>3.7 | 4.3<br>4.1  | V<br>V      | Functionality Mode: Normal<br>Functionality Mode: Extended<br>CUST_SETUP register bit 5          |
| $V_{SUP,UVhyst}$  | Undervoltage Detection Level Hysteresis <sup>2)</sup>                     | VSUPx | –            | 200        | –           | mV          |  |
| $V_{SUP,OV}$  | Overvoltage Detection Level   | VSUPx | 5.6<br>8.5   | 6.2<br>9.5 | 6.9<br>10.4 | V<br>V      | Functionality Mode: Normal<br>Functionality Mode: Extended<br>CUST_SETUP register bit 5          |
| $V_{SUP,OVhyst}$  | Overvoltage Detection Level Hysteresis <sup>2)</sup>                      | VSUPx | –            | 225        | –           | mV          |  |
| <b>Output Voltage in Case of Error Detection</b>  |   |       |              |            |             |             |  |
| $V_{SUP,DIAG}$  | Supply Voltage required to get defined Output Voltage Level <sup>2)</sup> | VSUPx | –            | 2.3        | –           | V           | Output behavior see Fig. 4–4 on page 35  |
| $V_{Error,Low}$   | Output Voltage Range of Lower Error Band <sup>2)</sup>                    | OUTx  | 0            | –          | 4           | % $V_{SUP}$ | $V_{SUP} > V_{SUP,DIAG}$<br>Analog Output<br>$5\text{ k}\Omega \leq R_L \leq 200\text{ k}\Omega$ |
| $V_{Error,High}$  | Output Voltage Range of Upper Error Band <sup>2)</sup>                    | OUTx  | 96           | –          | 100         | % $V_{SUP}$ | $V_{SUP} > V_{SUP,DIAG}$<br>Analog Output<br>$5\text{ k}\Omega \leq R_L \leq 200\text{ k}\Omega$ |
| <sup>1)</sup> Guaranteed by Design<br><sup>2)</sup> Characterized on small sample size, not tested. |   |       |              |            |             |             |  |

| Symbol  | Parameter  | Pin  | Limit Values |       |       | Unit        | Test Conditions   |
|---|--|------|--------------|-------|-------|-------------|---|
|   |  |      | Min.         | Typ.  | Max.  |             |   |
| <b>Output Short Detection Parameter</b>   |  |      |              |       |       |             |   |
| $t_{OCD}$   | Over Current Detection Time <sup>1)</sup>  | OUTx | –            | 128   | –     | $\mu$ s     |   |
| $t_{Timeout}$   | Time Period without Over Current Detection <sup>2)</sup>                         | OUTx | –            | 256   | –     | ms          |   |
| $I_{OVC}$   | Detectable Output Short Current <sup>1)</sup>                                    | OUTx | –            | 10    | –     | mA          |   |
| <b>HAR 3715 and HAR 372x (Analog Output)</b>  |  |      |              |       |       |             |   |
| $t_{OSD}$   | Overall Signal Delay <sup>1)</sup>   | OUTx | –            | 0.312 | 0.343 | ms          | Overall signal delay from magnetic field input to sensor output. Based on 8 kHz sample frequency      |
| DNL   | Differential Non-Linearity of D/A converter                                      | OUTx | –3           | 0     | 3     | LSB         |   |
| $E_R$   | Ratiometric Error of Output over temperature<br>(Error in $V_{OUT}/V_{SUP}$ )    | OUTx | –0.12        | 0     | 0.12  | %           | Max of [ $V_{OUT5} - V_{OUT4.5}$ and $V_{OUT5.5} - V_{OUT5}$ ] at $V_{OUT} = 10\%$ and $90\% V_{SUP}$ |
| INL   | Non-Linearity of D/A converter   | OUTx | –0.1         | 0     | 0.1   | %           | % of supply voltage   |
| $\Delta V_{OFFSET}$   | D/A converter offset drift over temperature range related to 25 °C <sup>2)</sup> | OUTx | –0.2         | 0     | 0.2   | % $V_{SUP}$ |   |
| $V_{OUTH}$  | Output High Voltage <sup>3)</sup>  | OUTx | 93           | –     | –     | % $V_{SUP}$ | $R_L$ Pull-up/-down = 5 k $\Omega$  |
| $V_{OUTL}$  | Output Low Voltage <sup>3)</sup>   | OUTx | –            | –     | 7     | % $V_{SUP}$ | $R_L$ Pull-up/-down = 5 k $\Omega$  |
| <sup>1)</sup> Guaranteed by Design<br><sup>2)</sup> Characterized on small sample size, not tested. |  |      |              |       |       |             |   |



| Symbol   | Parameter  | Pin  | Limit Values |      |      | Unit     | Test Conditions  |
|--|--|------|--------------|------|------|----------|--|
|  |  |      | Min.         | Typ. | Max. |          |  |
| $\Delta V_{OUTCL}$   | Accuracy of Output Voltage at Clamping Low Voltage over Temperature Range <sup>2)</sup>  | OUTx | -30          | 0    | 30   | mV       | $R_L$ Pull-up/-down = 5 k $\Omega$<br>$V_{SUP} = 5V$         |
| $\Delta V_{OUTCH}$   | Accuracy of Output Voltage at Clamping High Voltage over Temperature Range <sup>2)</sup> | OUTx | -30          | 0    | 30   | mV       |  |
| $OUT_{Noise}$  | Output Noise RMS <sup>2)5)</sup>   | OUTx | -            | 1.5  | 3.7  | mV       | Output range 10% to 90%                                      |
| $R_{OUT}$  | Output Resistance over Recommended Operating Range                                       | OUTx | -            | 1    | 10   | $\Omega$ | $V_{OUTLmax} \leq V_{OUT} \leq V_{OUTHmin}$                  |
| <b>Open-Circuit Detection</b>  |  |      |              |      |      |          |  |
| $V_{OUT}$  | Output voltage at open $V_{SUPx}$ line   | OUTx | 0            | 0    | 0.15 | V        | $V_{SUP} = 5 V$<br>$R_L^{4)} = 10 k\Omega$ to 200 k $\Omega$ |
|  |  |      | 0            | 0    | 0.2  | V        | $V_{SUP} = 5 V$<br>$5 k\Omega \geq R_L^{4)} < 10 k\Omega$    |
| $V_{OUT}$  | Output voltage at open GNDx line   | OUTx | 4.85         | 4.9  | 5.0  | V        | $V_{SUP} = 5 V$<br>$R_L^{4)} = 10 k\Omega$ to 200 k $\Omega$ |
|  |  |      | 4.8          | 4.9  | 5.0  | V        | $V_{SUP} = 5 V$<br>$5 k\Omega \geq R_L^{4)} < 10 k\Omega$    |
| <b>HAR 373x (Digital Output)</b>   |  |      |              |      |      |          |  |
| $V_{OUTH}$   | Output High Voltage  | OUTx | 4.8          | 4.9  | -    | V        | $V_{SUP} = 5 V$<br>$R_{Lpull-up/-down} = 5 k\Omega$          |
| $V_{OUTL}$   | Output Low Voltage   | OUTx | -            | 0.1  | 0.2  | V        | $V_{SUP} = 5 V$<br>$R_{Lpull-up/-down} = 5 k\Omega$          |
|  |  |      | -            | 0.4  | 0.65 | V        | <sup>2)</sup> $V_{SUP} = 5 V$<br>$R_{Lpull-up} = 1 k\Omega$  |
| $t_{rise}$   | Rise Time of Digital Output <sup>2)</sup>  | OUTx | -            | 0.2  | 0.4  | $\mu s$  | $V_{SUP} = 5 V, R_L$ Pull-up = 1 k $\Omega$<br>$C_L = 1 nF$  |
| <p><sup>2)</sup> Characterized on small sample size, not tested.</p> <p><sup>3)</sup> Signal band area with full accuracy is located between <math>V_{OUTL}</math> and <math>V_{OUTH}</math>. The sensors accuracy is reduced below <math>V_{OUTL}</math> and above <math>V_{OUTH}</math></p> <p><sup>4)</sup> RL can be pull-up or pull-down resistor</p> <p><sup>5)</sup> 4 kHz digital low-pass filter (LP-Filter = off): +/- 20 mT min. magnetic-field amplitude; <math>f_{BW} = 22.5</math> kHz</p> |  |      |              |      |      |          |  |

| Symbol  | Parameter   | Pin  | Limit Values              |                            |                            | Unit              | Test Conditions  |
|---|---|------|---------------------------|----------------------------|----------------------------|-------------------|--|
|   |   |      | Min.                      | Typ.                       | Max.                       |                   |  |
| $t_{fall}$  | Fall Time of Digital Output <sup>2)</sup>                         | OUTx | –                         | 0.25                       | 0.4                        | $\mu s$           | $V_{SUP} = 5 V$ , $R_{L Pull-up} = 1 k\Omega$<br>$C_L = 1 nF$  |
| ROUT_DIG  | On Resistance of Digital Pull-Up Driver                           | OUTx | –                         | 100                        | 200                        | $\Omega$          |  |
| <b>PWM Output</b>   |   |      |                           |                            |                            |                   |  |
| $t_{startup}$   | Start-up Time   | OUTx | –                         | 1.3                        | 1.7                        | ms                |  |
| $t_{OSD}$   | Overall Signal Delay <sup>1)</sup>                                | OUTx | –                         | 0.312                      | 0.343                      | ms                | Overall signal delay from magnetic-field input to sensor output. Transmission time of selected PWM frequency to be added.<br>Based on 8 kHz sample frequency |
| $OUT_{Noise}$   | Output Noise RMS <sup>1)2)</sup>                                  | OUTx | –                         | 0.03                       | 0.074                      | %                 | Output range 100% DC   |
| $f_{PWM}$   | PWM Frequency   | OUTx | 1800<br>900<br>450<br>180 | 2000<br>1000<br>500<br>200 | 2200<br>1100<br>550<br>220 | Hz                | Customer programmable  |
| $J_{PWM}$   | RMS PWM Jitter <sup>1)</sup>                                      | OUTx | –                         | 1                          | 2                          | LSB <sub>12</sub> | $f_{PWM} = 1 kHz$  |
| <b>SENT Output</b>  |   |      |                           |                            |                            |                   |  |
| $t_{tick}$  | Clock Tick Time   | OUTx | –                         | 2.75                       | –                          | $\mu s$           |  |
| $t_{nlow}$  | Nibble Low Time   | OUTx | –                         | 5                          | –                          | ttick             |  |
| $t_{sync}$  | Calibration / Synchronization Period                              | OUTx | –                         | 56                         | –                          | ttick             |  |
| $t_{nibble}$  | Status & Communication Nibble, Data Nibbles and CRC Nibble Period | OUTx | 12                        | –                          | 27                         | ttick             | $t_{nibble} = 12 + [status data CRC]$  |
| $t_{message}$   | Message Time  | OUTx | 116                       | –                          | 176                        | ttick             |  |
| $t_{pause}$   | Pause Period Time   | OUTx | 12                        | –                          | 70                         | ttick             |  |
| <sup>1)</sup> Characterized on small sample size, not tested<br><sup>2)</sup> 4 kHz digital low-pass filter (LP-Filter = off): +/- 20 mT min. magnetic-field amplitude; $f_{BW} = 22.5 kHz$ |   |      |                           |                            |                            |                   |  |

| Symbol                                 | Parameter                           | Pin          | Limit Values |      |      | Unit | Test Conditions                         |
|--|-------------------------------------|--------------|--------------|------|------|------|---|
|  |                                     |              | Min.         | Typ. | Max. |      |   |
| <b>SOIC8 Package</b>                   |                                     |              |              |      |      |      |   |
| R <sub>thja</sub>                      | Thermal Resistance Junction to Air  | –            | –            | –    | 116  | K/W  | Determined with a 1S1P board            |
|  |                                     | –            | –            | –    | 111  | K/W  | Determined with a 2S2P board            |
| R <sub>thjc</sub>                      | Thermal Resistance Junction to Case | –            | –            | –    | 30   | K/W  | Determined with a 1S1P and a 2S2P board |
| R <sub>I<sub>SOL</sub></sub>           | Isolation Resistance <sup>1)</sup>  | GND1<br>GND2 | 4            | –    | –    | MΩ   | Between two dies                        |
| 1) GND's galvanic isolation not tested |                                     |              |              |      |      |      |   |

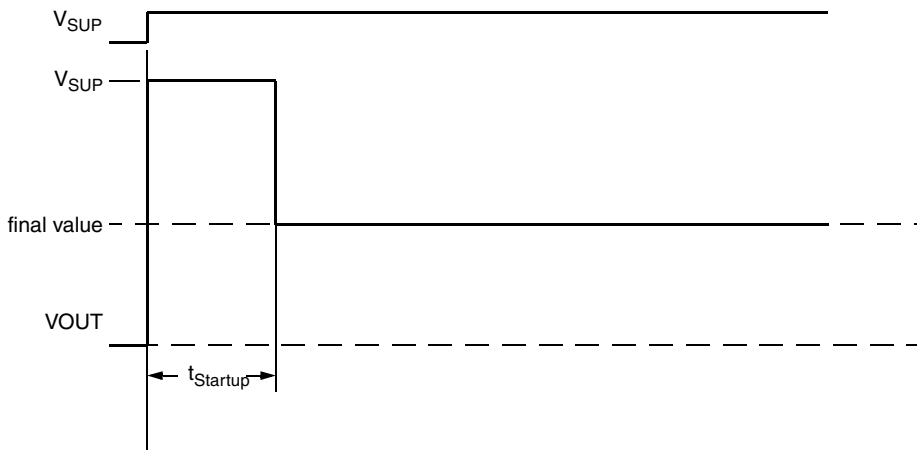


Fig. 4–3: POR timing

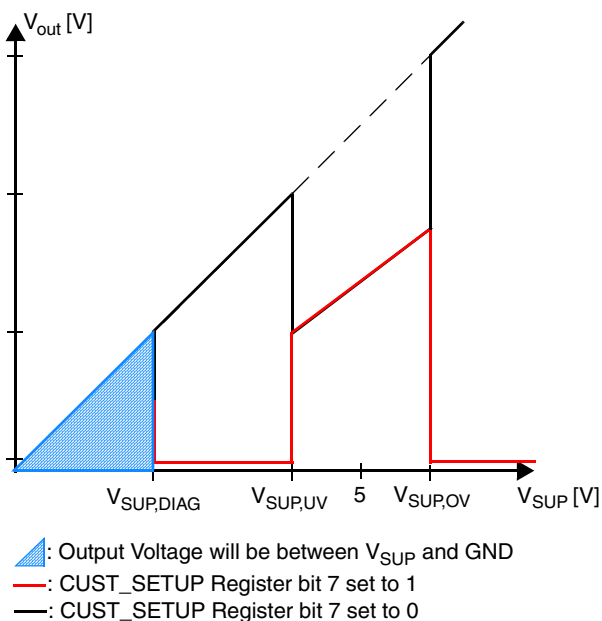


Fig. 4–4: Behavior of HAR 3715 and HAR 372x for different  $V_{SUP}$

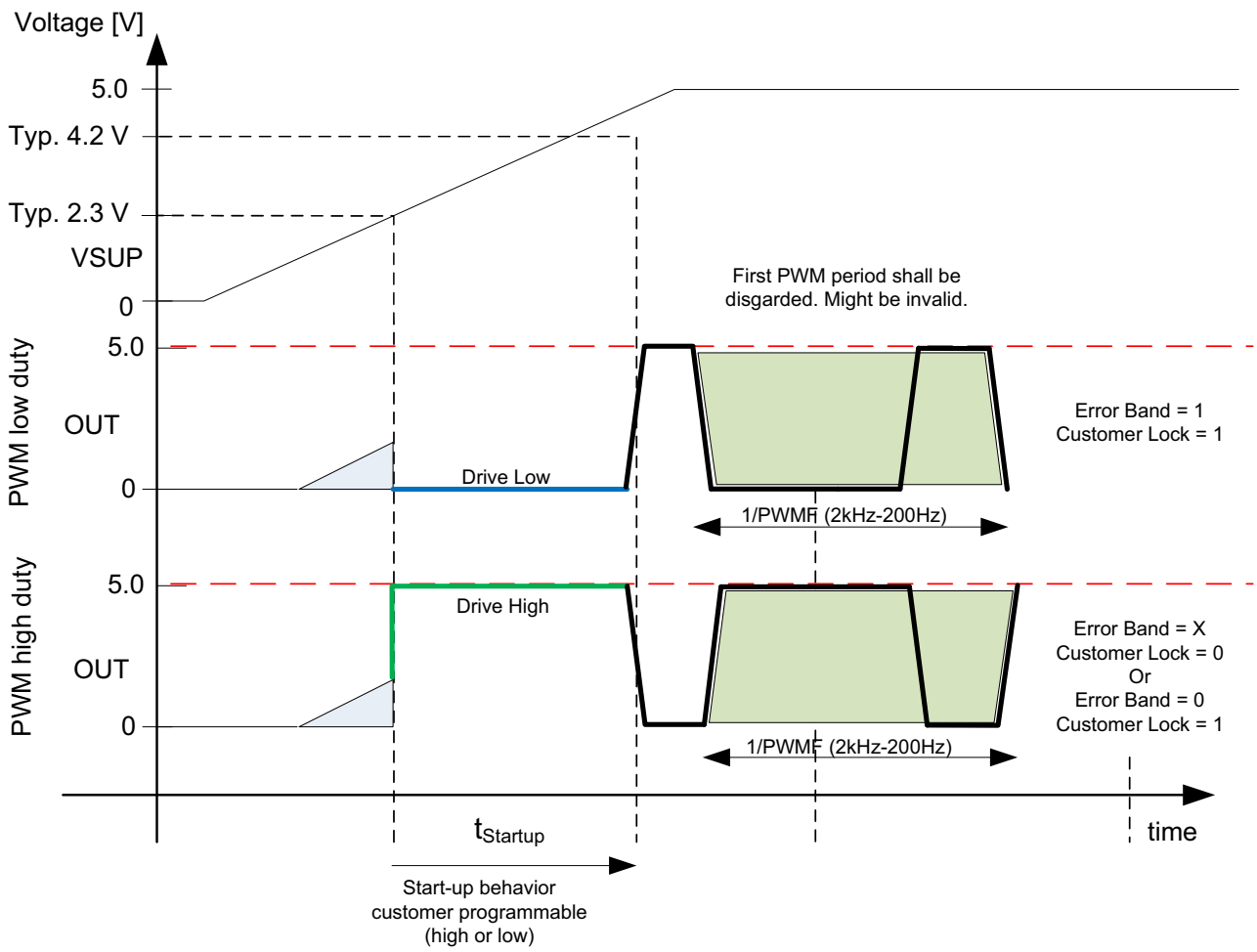


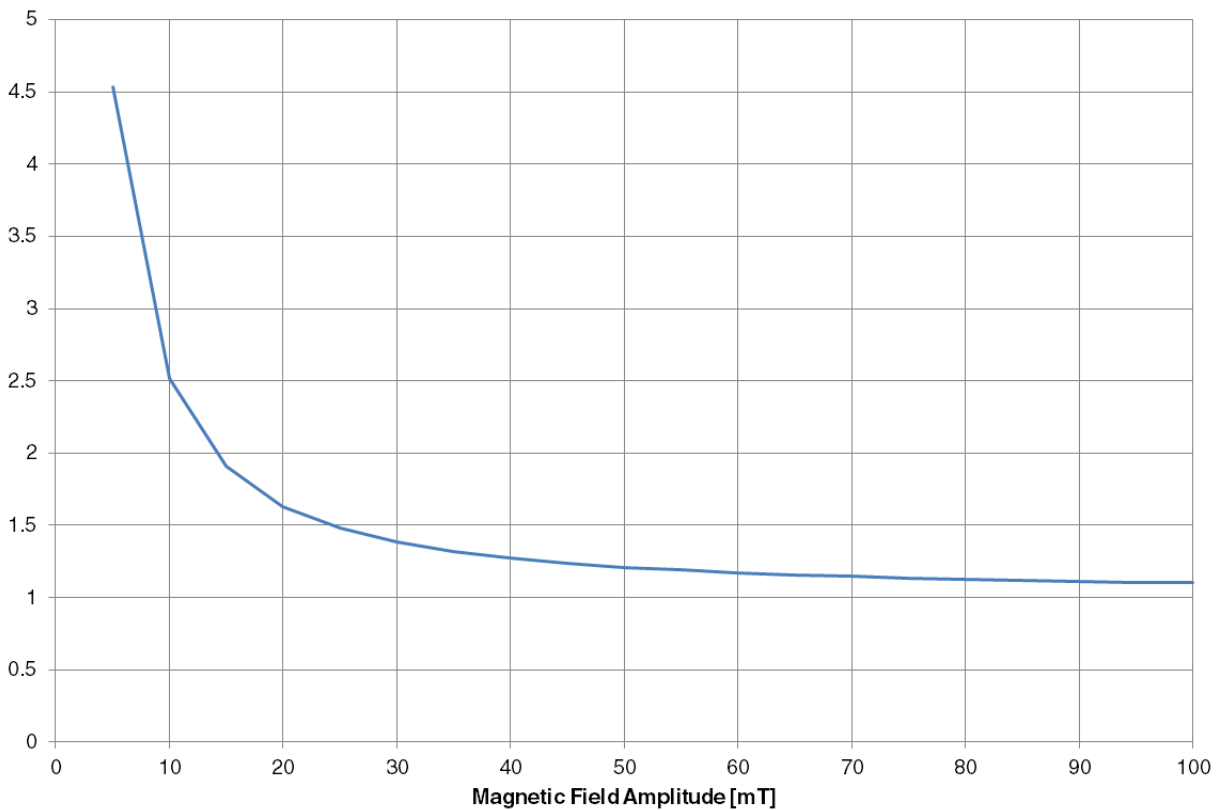
Fig. 4-5: Start-up behavior of HAR 373x with PWM output

## 4.10. Magnetic Characteristics

at  $T_J = -40\text{ °C}$  to  $170\text{ °C}$ ,  $V_{SUPx} = 4.5\text{ V}$  to  $5.5\text{ V}$ ,  $GNDx = 0\text{ V}$ , after programming and locking of the sensor, at Recommended Operation Conditions if not otherwise specified in the column "Conditions". Typical characteristics for  $T_J = 25\text{ °C}$  and  $V_{SUPx} = 5\text{ V}$ .

| Symbol  | Parameter  | Pin No. | Min.         | Typ.   | Max.       | Unit              | Test Conditions   |
|---|--|---------|--------------|--------|------------|-------------------|---|
| $\Theta_{RANGE}$  | Detectable angle range   | OUTx    | 0            | –      | 360        | °                 |   |
| $\Theta_{res}$  | Angle resolution   | OUTx    | –            | –      | 0.09       | °                 | (360°/4096)   |
| $E\Theta_{linxy}$   | XY angle linearity error (on output of CORDIC)                                     | OUTx    | –0.5         | –      | 0.5        | °                 | Min. $B_{AMP} = \pm 30\text{ mT}$ ,<br>$T_J = 25\text{ °C}$ <sup>1) 2) 3)</sup>   |
| $E\Theta_{linxy}$   | X/Y angle linearity error over temperature (on output of CORDIC)                   | OUTx    | –1.0         | –      | 1.0        | °                 | Min. $B_{AMP} = \pm 30\text{ mT}$ <sup>1) 2) 3)</sup><br>$T_J = -40 \dots 150\text{ °C}$<br>$T_J > 150 \dots 170\text{ °C}$ |
|   |  |         | –1.7         | –      | 1.7        | °                 |   |
| $E\Theta_{linxy}$   | X/Y angle linearity error over temperature (on output of CORDIC)                   | OUTx    | –1.5         | –      | 1.5        | °                 | Min. $B_{AMP} = \pm 20\text{ mT}$ <sup>1) 2) 3)</sup><br>$T_J = -40 \dots 150\text{ °C}$<br>$T_J > 150 \dots 170\text{ °C}$ |
|   |  |         | –2.4         | –      | 2.4        | °                 |   |
| $ASMm_{X/Y\_Z}$   | Absolute sensitivity mismatch on raw signals between X/Y and Z channel             | OUTx    | –3           | –      | 3          | %                 | $T_J = 25\text{ °C}$  |
| $Sense_{XYZ}$   | Sensitivity of X/Y and Z Hall Plate  | OUTx    | 118          | 128    | 138        | LSB/<br>mT        | $T_J = 25\text{ °C}$  |
| $SMm_{X/Y\_Z}$  | Thermal sensitivity mismatch drift of calibrated signals between X/Y and Z channel | OUTx    | –2.5<br>–3.5 | –<br>– | 2.5<br>3.5 | %<br>%            | related to $25\text{ °C}$ <sup>1)</sup><br>$T_J = -40 \dots 150\text{ °C}$<br>$T_J > 150 \dots 170\text{ °C}$               |
| $SMm_{XY}$  | Thermal sensitivity mismatch drift of calibrated signals between X and Y channel   | OUTx    | –2.0<br>–3.0 | –<br>– | 2.0<br>3.0 | %<br>%            | related to $25\text{ °C}$ <sup>1)</sup><br>$T_J = -40 \dots 150\text{ °C}$<br>$T_J > 150 \dots 170\text{ °C}$               |
| $Offset_{XY}$   | Offset of calibrated signals of X or Y channel                                     | OUTx    | –20          | –      | 20         | LSB <sub>15</sub> | $T_J = 25\text{ °C}$ <sup>1)</sup><br>Can be compensated in customer application  |
| $Offset_Z$  | Offset of calibrated signal of Z channel   | OUTx    | –12          | –      | 12         | LSB <sub>15</sub> | $T_J = 25\text{ °C}$ <sup>1)</sup><br>Can be compensated in customer application  |
| <sup>1)</sup> Characterized on sample base, 3-sigma values, not tested for each device<br><sup>2)</sup> Calculated angular error based on characterization and not on single error summation<br><sup>3)</sup> After optimal EOL calibration at room temperature |  |         |              |        |            |                   |   |

| Symbol   | Parameter   | Pin No. | Min.        | Typ. | Max.      | Unit                                   | Test Conditions  |
|--|---|---------|-------------|------|-----------|--|--|
| $\Delta\text{Offset}_{XY}$   | Offset drift of calibrated signals of X or Y channel  | OUTx    | -50<br>-100 | -    | 50<br>100 | LSB <sub>15</sub><br>LSB <sub>15</sub> | over full temperature range related to 25 °C <sup>1)</sup><br>T <sub>J</sub> = -40 ... 150°C<br>T <sub>J</sub> > 150 ... 170°C |
| $\Delta\text{Offset}_Z$  | Offset drift of calibrated signals of Z channel   | OUTx    | -10         | -    | 10        | LSB <sub>15</sub>                      | over full temperature range related to 25 °C <sup>1)</sup>   |
| $\Delta\text{SMm}_{XYZ\text{life}}$  | Relative sensitivity mismatch drift of calibrated signals between X or Y channel and Z channel over life time | OUTx    | -           | 1.0  | -         | %                                      | after 1000h HTOL <sup>1)</sup>   |
| $\Delta\text{Offset}_{XY\text{life}}$  | Offset drift of calibrated signals of X or Y channel  | OUTx    | -           | 30   | -         | LSB <sub>15</sub>                      | after 1000h HTOL <sup>1)</sup>   |
| $\Delta\text{Offset}_{Z\text{life}}$   | Offset drift of calibrated signal of Z channel  | OUTx    | -           | 5    | -         | LSB <sub>15</sub>                      | after 1000h HTOL <sup>1)</sup>   |
| <sup>1)</sup> Characterized on sample base, 3-sigma values, not tested for each device |   |         |             |      |           |  |  |



**Fig. 4-6:** Angular error versus magnetic-field amplitude over full temperature range for devices using X and Y magnetic-field component (for digital output)

## 5. Application Notes

### 5.1. Ambient Temperature

Due to the internal power dissipation, the temperature on the silicon chip (junction temperature  $T_J$ ) is higher than the temperature outside the package (ambient temperature  $T_A$ ).

$$T_J = T_A + \Delta T$$

The maximum ambient temperature is a function of power dissipation, maximum allowable die temperature and junction to ambient thermal resistance ( $R_{thja}$ ). With a maximum of 5.5 V operating supply voltage the power dissipation  $P$  is  $0.0825 \Omega$  per die, for a total of  $0.165 \Omega$ . The junction to ambient thermal resistance  $R_{thja}$  is specified in Section 4.9. on page 31.

The difference between junction and ambient air temperature is expressed by the following equation:

$$\Delta T = P * R_{thja}$$

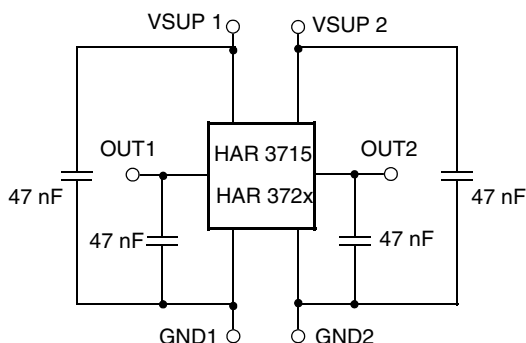
**Note** The calculated self-heating of the devices is only valid for the  $R_{th}$  test boards. Depending on the application setup the final results in an application environment might deviate from these values.

### 5.2. EMC and ESD

Please contact TDK-Micronas for detailed information on EMC and ESD results.

### 5.3. Application Circuit for HAR 3715 and HAR 372x

For EMC protection, it is recommended to connect one ceramic 47 nF capacitor each between ground and the supply voltage, respectively the output voltage pin.



**Fig. 5–1:** Recommended application circuit for HAR 3715 and HAR 372x

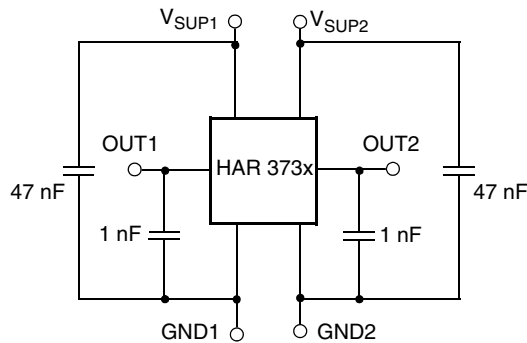
If the two dies are operated in parallel to the same supply and ground line, they can be programmed individually as the communication with the sensors is done via their output pins.

**Note** It is recommended to connect TEST1 to GND1 and TEST2 to GND2.

## 5.4. Application Circuit for HAR 373x

### PWM Output

In case of PWM output mode, it is recommended to connect one ceramic 47 nF capacitor between ground and the supply voltage and one ceramic 1 nF capacitor between the output pin and ground for EMC protection.



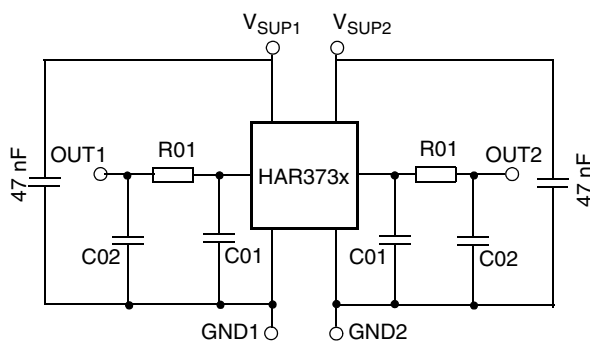
**Fig. 5–2:** Recommended application circuit for HAR 373x in PWM mode

### SENT Output

In case of SENT output mode, it is recommended to connect one ceramic 47 nF capacitor between ground and the supply voltage and a filter structure at the output pin for EMC protection as well for having a SENT standard compliant output slew rate.

Following two setups have been tested:

- C01 = 180 pF, C02 = 2.2 nF, R01 = 120  $\Omega$
- C01 = 180 pF, C02 = 3.3 nF, R01 = 180  $\Omega$



**Fig. 5–3:** Recommended application circuit for HAR 373x

If the two dies are operated in parallel to the same supply and ground line, they can be programmed individually as the communication with the sensors is done via their output pins.

**Note** It is recommended to connect TEST1 to GND1 and TEST2 to GND2.



### 5.5. Measurement of a PWM Output Signal of HAR 373x

In case of the PWM output, the magnetic-field information is coded in the duty cycle of the PWM signal. The duty cycle is defined as the ratio between the high time “s” and the period “d” of the PWM signal (see Fig. 5–4).

**Note** The PWM signal is updated with the rising edge. Hence, for signal evaluation, the trigger-level must be the rising edge of the PWM signal.

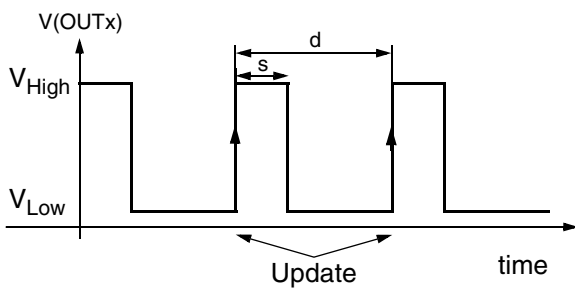


Fig. 5–4: Definition of PWM signal

### 5.6. Recommended Pad Size SOIC8 Package

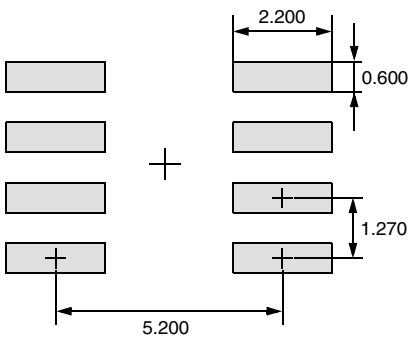


Fig. 5–5: Recommended Pad Size dimensions in mm

## 6. Programming of the Sensor

HAR 37xy features two different customer modes. In Application Mode the sensors provide a ratiometric analog output voltage or a digital output signal (PWM or SENT). In Programming Mode it is possible to change the register settings of the sensor.

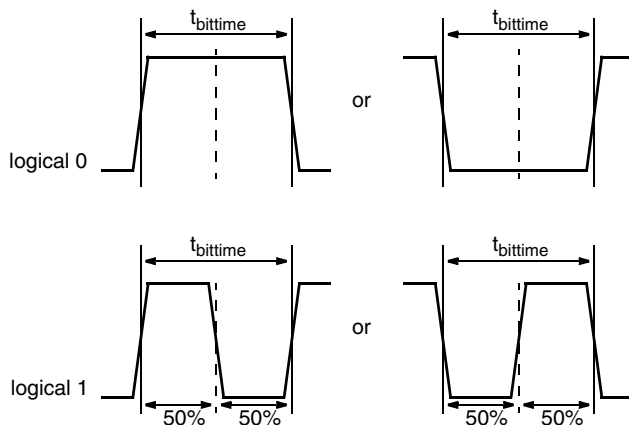
After power-up the sensor is always operating in the Application Mode. It is switched to the Programming Mode by a pulse at the sensor output pin.

### 6.1. Programming Interface

In Programming Mode HAR 37xy is addressed by modulating a serial telegram on the sensors output pin. Both sensors answer with a modulation of the output voltage.

A logical “0” is coded as no level change within the bit time. A logical “1” is coded as a level change of typically 50% of the bit time. After each bit, a level change occurs (see Fig. 6–1).

The serial telegram is used to transmit the EEPROM content, error codes and digital values of the angle information from and to the sensor.



**Fig. 6–1:** Definition of logical 0 and 1 bit

A description of the communication protocol and the programming of the sensor is available in a separate document (HAL/HAR 37xy Programming Guide).

**Table 6–1:** Telegram parameters (All voltages are referenced to GNDx.)

| Symbol                  | Parameter  | Pin No. | Limit Values         |      |                      | Unit | Test Conditions   |
|-------------------------|--|---------|----------------------|------|----------------------|------|---|
|                         |  |         | Min.                 | Typ. | Max.                 |      |   |
| V <sub>OUTL</sub>       | Voltage for Output Low Level during Programming through Sensor Output Pin    | OUTx    | 0                    | –    | 0.2*V <sub>SUP</sub> | V    | for V <sub>SUP</sub> = 5 V  |
|                         |  |         | 0                    |      | 1                    | V    |   |
| V <sub>OUTH</sub>       | Voltage for Output High Level during Programming through Sensor Output Pin   | OUTx    | 0.8*V <sub>SUP</sub> | –    | V <sub>SUP</sub>     | V    | for V <sub>SUP</sub> = 5 V  |
|                         |  |         | 4                    | –    | 5.0                  | V    |   |
| V <sub>SUPProgram</sub> | V <sub>SUP</sub> Voltage for EEPROM & NVRAM programming (during Programming) | VSUPx   | 5.7                  | 6.0  | 6.5                  | V    | Supply voltage for bidirectional communication via output pin as well as for 3-wire communication via supply voltage modulation |
| t <sub>bittime</sub>    | Biphase Bit Time   | OUTx    | 900                  | 1000 | 1100                 | μs   | Cust. programmable, T <sub>J</sub> = 25°C<br>Bit 13 of Customer Setup = 0<br>Bit 13 of Customer Setup = 1                       |
|                         |  |         | 225                  | 250  | 275                  |      |   |
|                         | Slew rate  | OUTx    | –                    | 2    | –                    | V/μs |   |

## 6.2. Programming Environment and Tools

For the programming of HAR 37xy during product development a programming tool including hardware and software is available on request. It is recommended to use the TDK-Micronas' tool kit (TDK-MSP V1.x or USB-Kit and LabVIEW™ Programming Environment) in order to facilitate the product development. The details of programming sequences are described in the "HAL 37xy, HAR 372x, HAR 373x User Manual".

### 6.3. Programming Information

For production and qualification tests, it is mandatory to set the LOCK bit to one and the POUT bit to zero after final adjustment and programming of HAR 37xy.

Before locking the device, it is recommended to read back all register values to ensure that the intended data is correctly stored in the sensor's memory. Alternatively, it is also possible to cross-check the sensor output signal with the intended output behavior.

The success of the LOCK process shall be checked by reading the status of the LOCK bit after locking.

It is also mandatory to check the acknowledge (first and second) of the sensor after each write and store sequence to verify if the programming of the sensor was successful. To enable debugging of the production line, it is recommended to read back the PROG\_DIAGNOSIS register in case of a missing second acknowledge. Please check "HAL/HAR 37xy Programming Guide" for further details.

Electrostatic Discharges (ESD) may disturb the programming pulses. Please take precautions against ESD.

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**Note** Please check also the "HAL 37xy, HAR 372x, HAR 373x User Manual" and relevant documentation for the TDK-MSP V1.x or USB-Kit. It contains additional information and instructions about the programming of the devices.

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## 7. Document History

1. "HAR 3715, HAR 372x, HAR 373x Robust Dual-Die Programmable 2D Position Sensor Family with Arbitrary Output Function", June 17, 2015, AI000180\_001EN.  
First release of the advance information.

2. "HAR 3715, HAR 372x, HAR 373x Robust Dual-Die Programmable 2D Position Sensor Family with Arbitrary Output Function", Jan. 18, 2016, DSH000175\_001EN.  
First release of the data sheet.

### Major changes:

- Assembly and storage information changed
- Absolute maximum ratings:  
ESD protection voltages changed
- Magnetic characteristics: values changed

3. "HAR 3715, HAR 372x, HAR 373x Robust Dual-Die Programmable 2D Position Sensor Family with Arbitrary Output Function", May 5, 2017, DSH000175\_002EN.  
Second release of the data sheet.

### Major changes:

- Update of some electrical parameters
- Storage temperature added
- Graph with start-up behavior in PWM mode added

4. "HAR 3715, HAR 372x, HAR 373x Robust Dual-Die Programmable 2D Position Sensor Family with Arbitrary Output Function", Oct. 25, 2019, DSH000175\_003EN.  
Second release of the data sheet.

### Major changes:

- Disclaimer updated
- Figure 2-1 "Ordering Code Principle" updated
- Figure 3-2 "Signal path of HAR 37xy (equal for both dies)" updated
- Figure 4-1 "Package Drawing" updated
- Section 4.4 "Size of Sensitive Area"
- Section 4.5 "Definition of Magnetic-Field Vectors" updated
- Section 4.3.3 "Package Parameters and Position" deleted
- Table "Pin Connections and Short Description" updated
- Table "Absolute Maximum Ratings" updated
- Recommended Operating Condition  $T_J$  updated
- Table "Characteristic Parameters" updated
- Table "Magnetic Characteristics" updated
- Section 6.2 "Programming Environment and Tools" updated
- Section 6.3 "Programming Information" updated